N-channel TrenchMOS logic level FET

Rev. 04 — 5 June 2009

Product data sheet

1. Product profile

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Simple gate drive required due to low gate charge

1.3 Applications

DC-to-DC convertors

 Suitable for logic level gate drive sources

Switched-mode power supplies

1.4 Quick reference data

	Quick reference					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	-	25	V
I _D	drain current	T _{mb} = 25 °C; V _{GS} = 5 V; see <u>Figure 1</u> ; see <u>Figure 3</u>	-	-	75	A
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	187	W
Avalance	e ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy		-	-	180	mJ
Dynamic	characteristics					
Q _{GD}	gate-drain charge	$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A};$ $V_{DS} = 12 \text{ V}; T_j = 25 \text{ °C}; \text{ see}$ <u>Figure 12</u> ; see <u>Figure 13</u>	-	5.6	-	nC
Static ch	aracteristics					
R _{DSon}	drain-source on-state resistance	V_{GS} = 10 V; I_D = 25 A; T_j = 25 °C; see <u>Figure 10</u> ; see <u>Figure 11</u>	-	5.3	6	mΩ



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2. Pinning information

Table 2.	Pinning	information			
Pin	Symbol	Description		Simplified outline	Graphic symbol
1	G	gate			-
2	D	drain	[1]	mb	
3	S	source			
mb	D	mounting base; connected to drain			mbb076 S
				SOT428 (SC-63; DPAK)	

[1] It is not possible to make a connection to pin 2.

3. Ordering information

Table 3.Ordering information

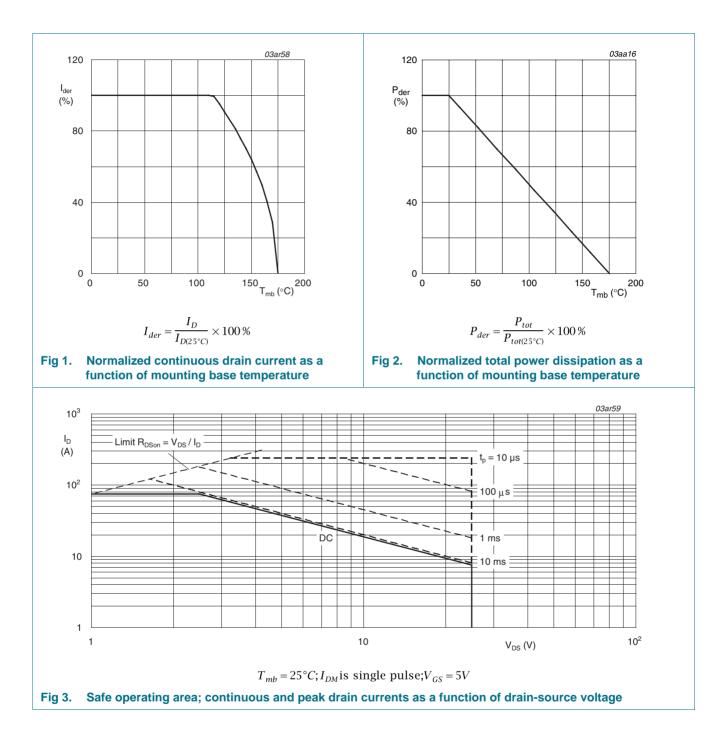
Type number	Package					
	Name	Description	Version			
PHD108NQ03LT	SC-63; DPAK	plastic single-ended surface-mounted package (DPAK); 3 leads (one lead cropped)	SOT428			

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	25	V
V _{DGR}	drain-gate voltage	T _j ≥ 25 °C; T _j ≤ 175 °C; R _{GS} = 20 kΩ	-	25	V
V _{GS}	gate-source voltage		-20	20	V
I _D	drain current	$V_{GS} = 5 \text{ V}; T_{mb} = 25 \text{ °C}; \text{ see } Figure 1; \text{ see } Figure 3$	-	75	А
		$V_{GS} = 5 \text{ V}; \text{ T}_{mb} = 100 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{100 \text{ Figure 1}}$	-	75	А
I _{DM}	peak drain current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$; see Figure 3	-	240	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	187	W
T _{stg}	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
Source-dr	ain diode				
I _S	source current	T _{mb} = 25 °C	-	75	А
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^\circ C$	-	240	А
Avalance	uggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 43 A; V_{sup} ≤ 25 V; unclamped; t_p = 0.25 ms; R_{GS} = 50 Ω	-	180	mJ



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5. Thermal characteristics

Table 5.	Thermal characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{\text{th(j-mb)}}$	thermal resistance from junction to mounting base	see <u>Figure 4</u>	-	-	0.8	K/W
R _{th(j-a)}	thermal resistance from junction to ambient	minimum footprint; mounted on a printed-circuit board; vertical in still air	-	75	-	K/W
		mounted on a printed-circuit board; vertical in still air; SOT404 minimum footprint	-	50	-	K/W

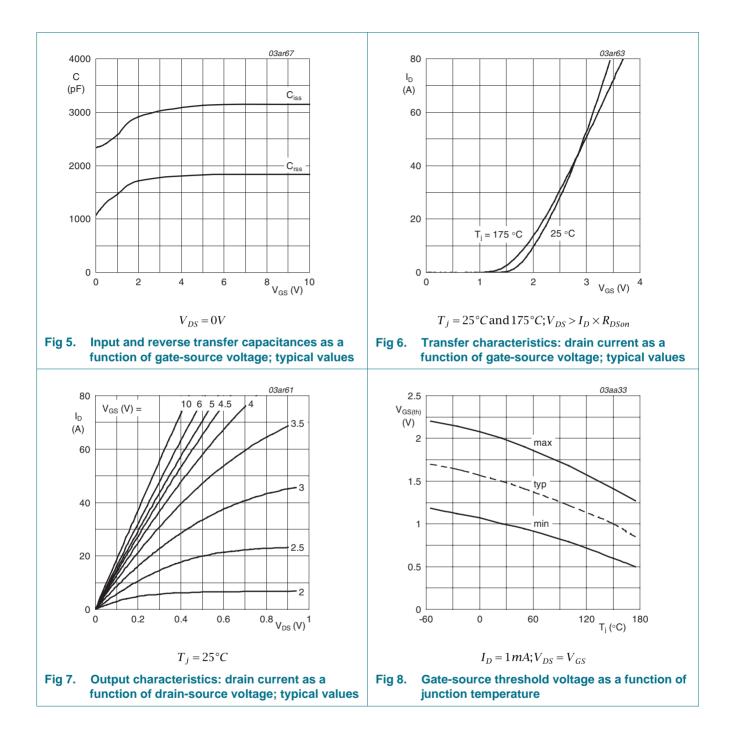


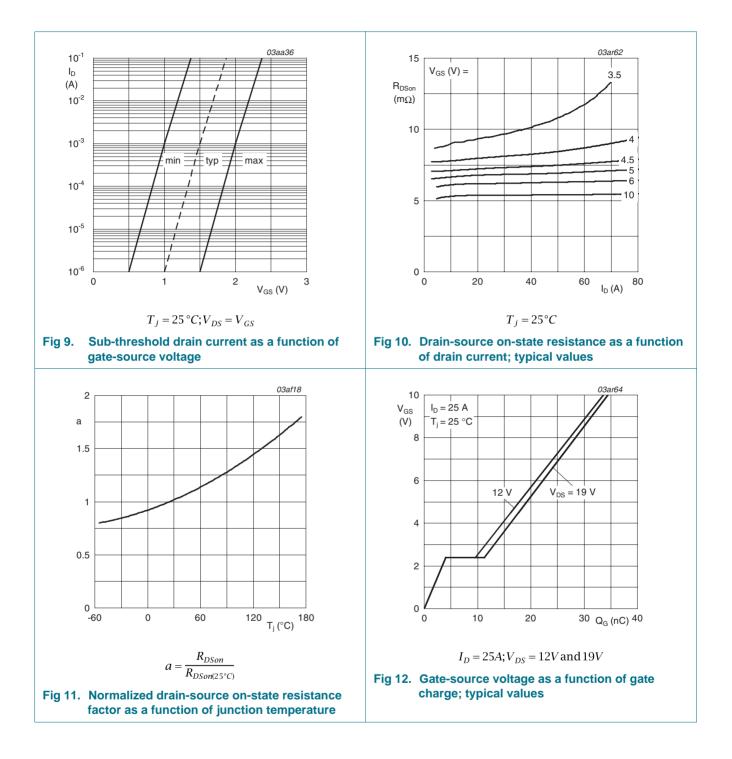
6. Characteristics

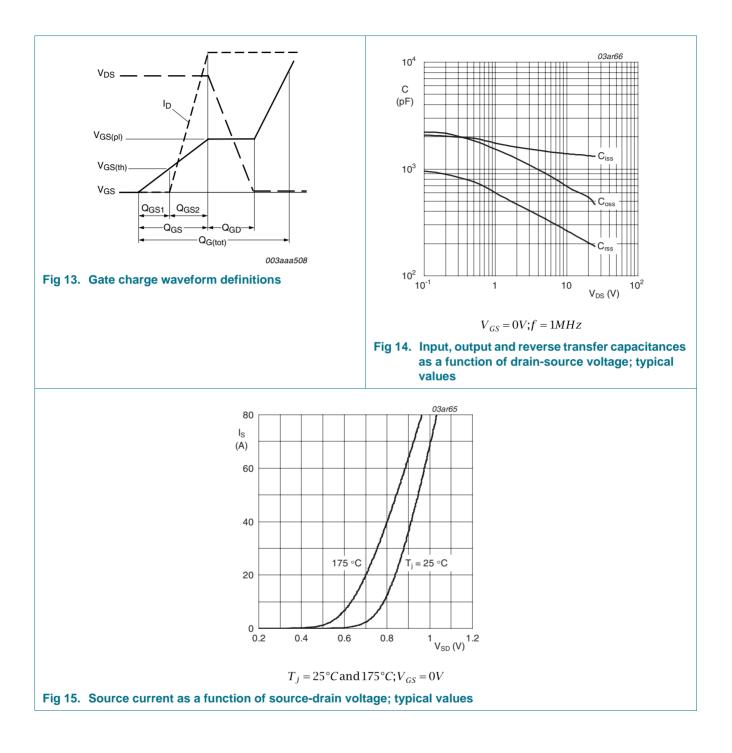
Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
V _{(BR)DSS}	drain-source	$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^\circ C$	25	-	-	V
	breakdown voltage	$I_D = 250 \ \mu\text{A}; \ V_{GS} = 0 \ V; \ T_j = -55 \ ^\circ\text{C}$	22	-	-	V
V _{GS(th)} gate-sou voltage	gate-source threshold voltage	I _D = 1 mA; V _{DS} = V _{GS} ; T _j = 25 °C; see <u>Figure 8</u> ; see <u>Figure 9</u>	1	1.5	2	V
		I _D = 1 mA; V _{DS} = V _{GS} ; T _j = 175 °C; see <u>Figure 8</u> ; see <u>Figure 9</u>	0.5	-	-	V
		I _D = 1 mA; V _{DS} = V _{GS} ; T _j = -55 °C; see <u>Figure 8</u> ; see <u>Figure 9</u>	-	-	2.2	V
I _{DSS}	drain leakage current	$V_{DS} = 25 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1	μA
		$V_{DS} = 25 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	500	μA
I _{GSS}	gate leakage current	$V_{GS} = 10 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.02	100	nA
		V_{GS} = -10 V; V_{DS} = 0 V; T_j = 25 °C	-	0.02	100	nA

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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{DSon}	drain-source on-state resistance	V_{GS} = 5 V; I_D = 25 A; T_j = 25 °C; see <u>Figure 10</u> ; see <u>Figure 11</u>	-	6.7	7.5	mΩ
		$V_{GS} = 5 \text{ V}; I_D = 25 \text{ A}; T_j = 175 \text{ °C}; \text{ see}$ Figure 10; see Figure 11	-	12.1	13.5	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C}; \text{ see}$ Figure 10; see Figure 11	-	5.3	6	mΩ
R _G	internal gate resistance (AC)	f = 1 MHz; T _j = 25 °C	-	1.2	-	Ω
Dynamic of	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 12}{\text{Figure } 12}; \text{ see } \frac{\text{Figure } 13}{\text{Figure } 13}$	-	16.3	-	nC
		$ I_D = 0 \text{ A}; \text{V}_{DS} = 0 \text{ V}; \text{V}_{GS} = 4.5 \text{ V}; T_j = 25 ^\circ\text{C} $	-	12.5	-	nC
Q _{GS}	gate-source charge	$I_D = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$	-	4	-	nC
Q _{GS1}	pre-threshold gate-source charge	T _j = 25 °C; see <u>Figure 12</u> ; see <u>Figure 13</u>	-	2.5	-	nC
Q _{GS2}	post-threshold gate-source charge		-	1.5	-	nC
Q _{GD}	gate-drain charge		-	5.6	-	nC
V _{GS(pl)}	gate-source plateau voltage	$I_D = 25 \text{ A}$; $V_{DS} = 12 \text{ V}$; $T_j = 25 \text{ °C}$; see Figure 12; see Figure 13	-	2.4	-	V
C _{iss} input capacitance	$V_{DS} = 12 V$; $V_{GS} = 0 V$; f = 1 MHz; T _j = 25 °C; see <u>Figure 14</u>	-	1375	-	pF	
		$V_{DS} = 0 V$; $V_{GS} = 0 V$; $f = 1 MHz$; $T_j = 25 °C$; see <u>Figure 14</u>	-	2120	-	pF
Coss	output capacitance	V_{DS} = 12 V; V_{GS} = 0 V; f = 1 MHz;	-	640	-	pF
C _{rss}	reverse transfer capacitance	T _j = 25 °C; see <u>Figure 14</u>	-	250	-	pF
t _{d(on)}	turn-on delay time	V_{DS} = 12 V; R_L = 0.5 $\Omega;~V_{GS}$ = 4.5 V;	-	15	-	ns
t _r	rise time	$R_{G(ext)} = 5.6 \ \Omega; \ T_j = 25 \ ^{\circ}C$	-	38	-	ns
t _{d(off)}	turn-off delay time		-	32	-	ns
t _f	fall time		-	25	-	ns
Source-dr	ain diode					
V _{SD}	source-drain voltage	I _S = 25 A; V _{GS} = 0 V; T _j = 25 °C; see <u>Figure 15</u>	-	0.86	1.2	V
t _{rr}	reverse recovery time	$I_{S} = 20 \text{ A}; \text{ d}I_{S}/\text{d}t = -100 \text{ A}/\mu\text{s}; \text{ V}_{GS} = 0 \text{ V};$	-	34	-	ns
Q _r	recovered charge	V _{DS} = 25 V; T _j = 25 °C	-	21	-	nC







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7. Package outline

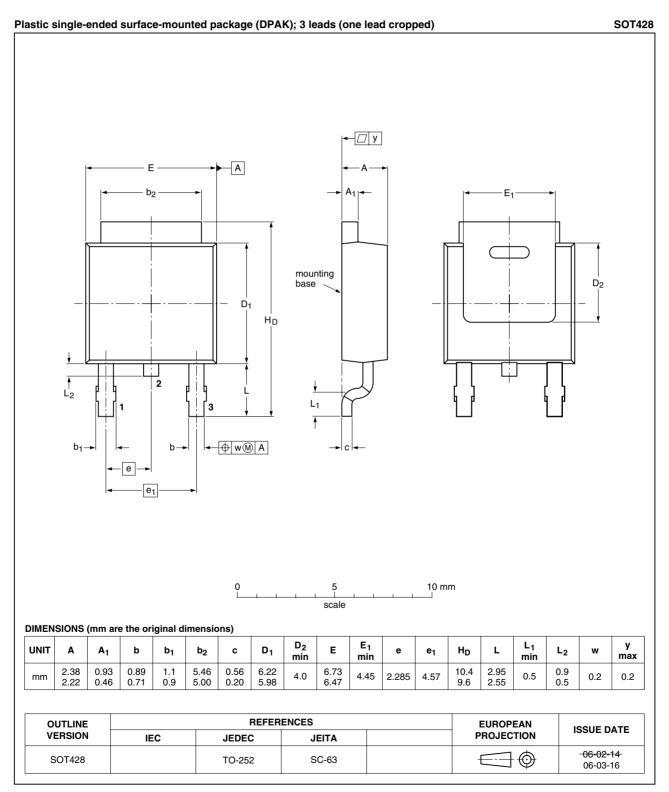


Fig 16. Package outline SOT428 (DPAK)

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8. Revision history

Table 7.	Revision history				
Document ID		Release date	Data sheet status	Change notice	Supersedes
PHD108N	Q03LT_4	20090605	Product data sheet	-	PHB_PHD_PHU108NQ03LT_3
Modifications:			t of this data sheet ha of NXP Semiconduct	0	to comply with the new identity
		 Legal texts 	have been adapted	to the new compan	y name where appropriate.
		• •	per PHD108NQ03LT s _PHU108NQ03LT_3.	-	a sheet
PHB_PHE (9397 750	D_PHU108NQ03LT_3 14707)	20050418	Product data sheet	2004070095	PHP_PHB_PHD108NQ03LT-02
PHP_PHB_PHD108NQ03LT-02 (9397 750 10159)		20020911	Product data	-	PHP_PHB_PHD108NQ03LT-01
PHP_PHB_PHD108NQ03LT-01 (9397 750 09065)		20011218	Product data	-	-

9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions"

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